

May 2001

# FQP45N03L

## 30V LOGIC N-Channel MOSFET

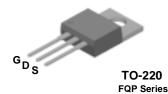
### **General Description**

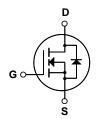
These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as DC/DC converters, high efficiency switching for power management in portable and battery operated products.

#### **Features**

- 45A, 30V,  $R_{DS(on)}$  = 0.018 $\Omega$  @V<sub>GS</sub> = 10 V Low gate charge ( typical 15 nC)
- Low Crss (typical 105 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability
- 175°C maximum junction temperature rating





# Absolute Maximum Ratings T<sub>C</sub> = 25°C unless otherwise noted

Symbol	Parameter		FQP45N03L	Units
$V_{DSS}$	Drain-Source Voltage		30	V
I <sub>D</sub>	Drain Current - Continuous (T <sub>C</sub> = 25°	°C)	45	А
	- Continuous (T <sub>C</sub> = 100°C)		31.8	Α
I <sub>DM</sub>	Drain Current - Pulsed	(Note 1)	180	А
$V_{GSS}$	Gate-Source Voltage		± 20	V
E <sub>AS</sub>	Single Pulsed Avalanche Energy	(Note 2)	200	mJ
I <sub>AR</sub>	Avalanche Current	(Note 1)	45	Α
E <sub>AR</sub>	Repetitive Avalanche Energy	(Note 1)	7.5	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	7.0	V/ns
P <sub>D</sub>	Power Dissipation (T <sub>C</sub> = 25°C)		75	W
	- Derate above 25°C		0.5	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +175	°C
T <sub>L</sub>	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

# **Thermal Characteristics**

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		2.0	°C/W
$R_{\theta CS}$	Thermal Resistance, Case-to-Sink	0.5		°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	racteristics					
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V
ΔBV <sub>DSS</sub>		$I_D = 250 \mu A$ , Referenced to				V
/ $\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	$_{1D} = 250 \mu\text{A}$ , Referenced to $_{25}^{\circ}\text{C}$		0.03		V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V			1	μΑ
		V <sub>DS</sub> = 24 V, T <sub>C</sub> = 150°C			10	μΑ
I <sub>GSSF</sub>	Gate-Body Leakage Current, Forward	V <sub>GS</sub> = 20 V, V <sub>DS</sub> = 0 V			100	nA
I <sub>GSSR</sub>	Gate-Body Leakage Current, Reverse	V <sub>GS</sub> = -20 V, V <sub>DS</sub> = 0 V			-100	nA
On Cha	racteristics					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	1.0		2.5	V
R <sub>DS(on)</sub>	Static Drain-Source	$V_{GS} = 10 \text{ V}, I_D = 22.5 \text{ A}$		0.0136	0.018	
. (DS(on)	On-Resistance	V <sub>GS</sub> = 5 V, I <sub>D</sub> = 22.5 A		0.0192	0.025	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 15 V, I <sub>D</sub> = 22.5 A (Note 4)		24.3		S
Dynam	ic Characteristics					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V,		780	1000	pF
C <sub>oss</sub>	Output Capacitance	f = 1.0 MHz		420	550	pF
C <sub>rss</sub>	Reverse Transfer Capacitance			105	140	pF
Switchi	ng Characteristics					
t <sub>d(on)</sub>	Turn-On Delay Time	V - 15 V I - 22 5 A		15	40	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 15 \text{ V}, I_{D} = 22.5 \text{ A},$ $R_{G} = 25 \Omega$		130	270	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	NG = 23 22		7.5	25	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4, 5)		60	130	ns
Qg	Total Gate Charge	V <sub>DS</sub> = 24 V, I <sub>D</sub> = 45 A,		15	20	nC
Q <sub>gs</sub>	Gate-Source Charge	V <sub>GS</sub> = 5 V		5.0		nC
Q <sub>gd</sub>	Gate-Drain Charge	(Note 4, 5)		8.0		nC
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Drain-S	Source Diode Characteristics at Maximum Continuous Drain-Source Did				45	Α
I <sub>SM</sub>	Maximum Pulsed Drain-Source Diode Forward Current				180	A
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 45 A			1.5	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_{S} = 45 \text{ A,}$		35		ns
Q <sub>rr</sub>	Reverse Recovery Charge	$dI_F / dt = 100 \text{ A/}\mu\text{s}$ (Note 4)		30		nC

- Notes: 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 98µH,  $I_{AS}$  = 45A,  $V_{DD}$  = 15V,  $R_G$  = 25  $\Omega$ , Starting  $T_J$  = 25°C 3.  $I_{SD}$  ≤ 45A, di/dt ≤ 300A/us,  $V_{DD}$  ≤ BV<sub>DSS</sub>, Starting  $T_J$  = 25°C 4. Pulse Test : Pulse width ≤ 300µs, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

# **Typical Characteristics**

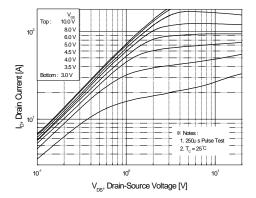


Figure 1. On-Region Characteristics

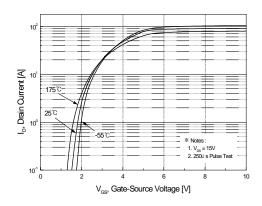


Figure 2. Transfer Characteristics

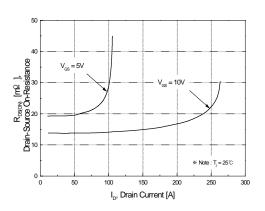


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

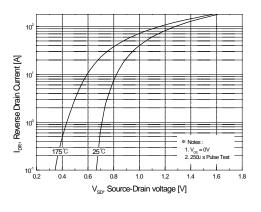


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

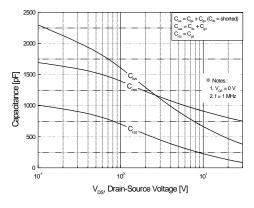


Figure 5. Capacitance Characteristics

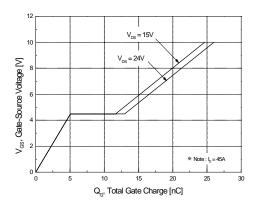


Figure 6. Gate Charge Characteristics

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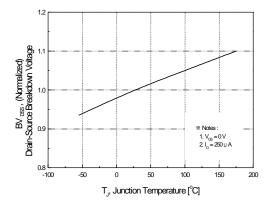
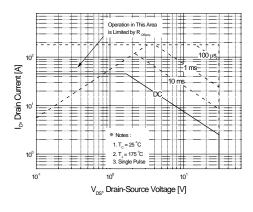


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



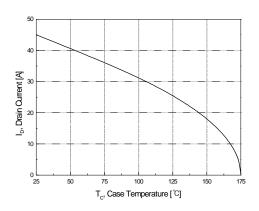


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

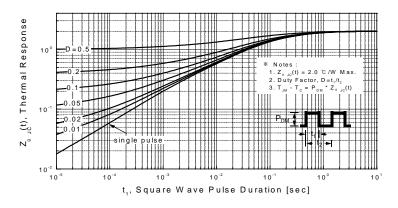
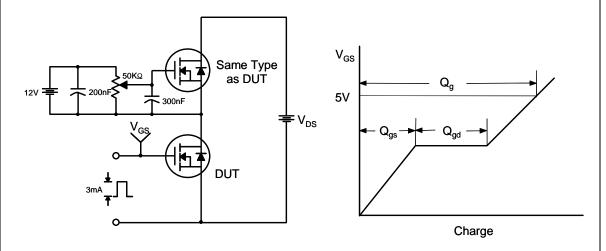


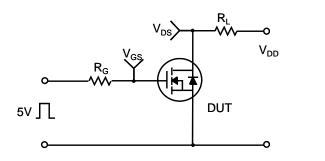
Figure 11. Transient Thermal Response Curve

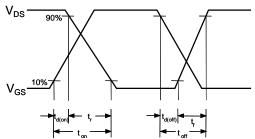
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# **Gate Charge Test Circuit & Waveform**

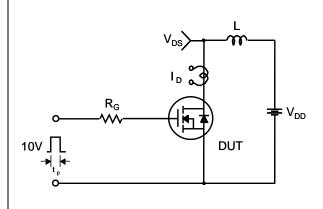


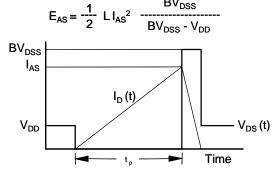
## **Resistive Switching Test Circuit & Waveforms**



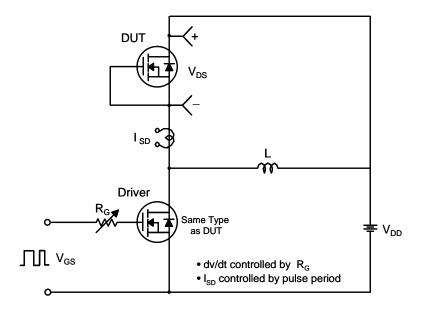


# **Unclamped Inductive Switching Test Circuit & Waveforms**

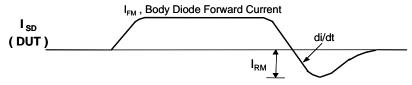




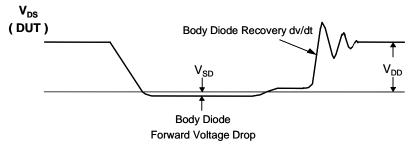
#### Peak Diode Recovery dv/dt Test Circuit & Waveforms

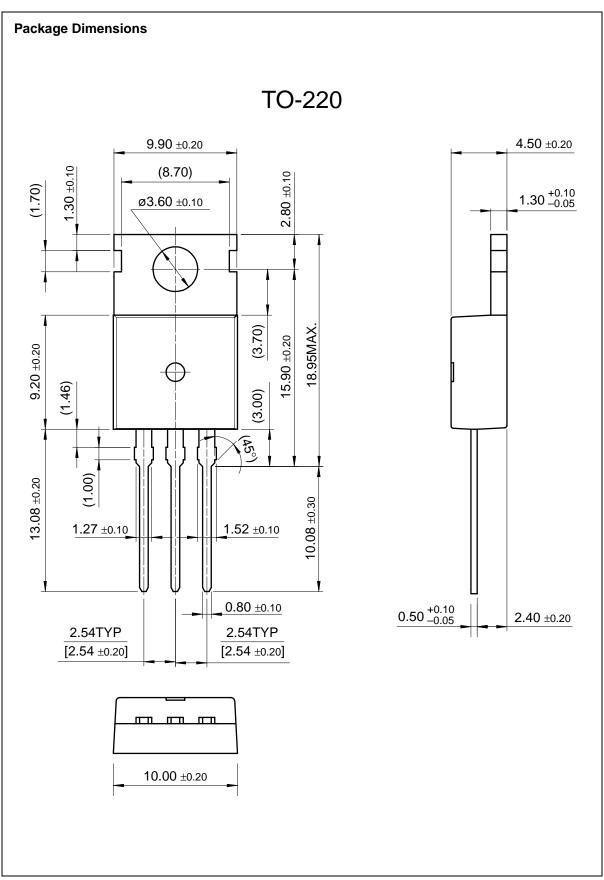






Body Diode Reverse Current





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